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Reflection, Scattering, and Diffraction from Surfaces VII

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Contents

THEORY AND MODELING I

11485 08 **Induced polarization response within a spheroidal particle from an incident electromagnetic wave** [11485-6]

INSTRUMENTATION AND APPLICATIONS I

11485 0A **BSDF measurements and analyses of specular samples using a table-top goniometer in support of remote sensing instruments** [11485-8]

11485 0B **Augmenting CASI® BRDF measurement device to measure out-of-plane scatter with CCD pixel array** [11485-9]

MEASUREMENT METHODOLOGY

11485 0D **Direct method of extracting complex refractive index from routine Fourier transform infrared reflectance/transmittance measurements (Invited Paper)** [11485-11]

11485 0E **Modal imaging of a laser Gaussian-beam reflected off a surface** [11485-12]

THEORY AND MODELING II

11485 0J **pySCATMECH: a Python interface to the SCATMECH library of scattering codes** [11485-17]

INSTRUMENTATION AND APPLICATIONS II

11485 0K **High temperature reflectometer for spatially resolved spectral directional emissivity of laser powder bed fusion processes** [11485-18]

POSTER SESSION

11485 0N **Signal-to-noise ratio evaluation for the nanometer-scale patterned defect inspection using dark-field microscopy with tailored polarization illumination** [11485-21]

11485 0O **High-dynamic-range instrument for characterisation of the angle-dependent reflectivity of ITER plasma-facing components** [11485-22]

11485 0P **Performance enhancement of WDM-PONs: Interferometric noise reduction** [11485-23]